

Serial EEPROM series Standard EEPROM **MicroWire BUS EEPROM (3-Wire)**

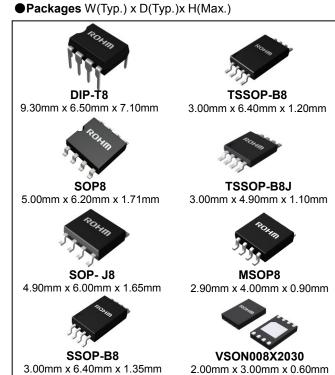
BR93G86-3B

General Description

BR93G86-3B is serial EEPROM of serial 3-line Interface method. They are 16bit organization and CS PIN is the third PIN in their PIN configuration.

Features

- 3-line communications of chip select, serial clock, serial data input / output (the case where input and output are shared)
- Operations available at high speed 3MHz clock (4.5V ~ 5.5V)
- High speed write available (write time 5ms max.)
- Same package and pin configuration from 1Kbit to 16Kbit
- 1.7~5.5V single power source operation
- Address auto increment function at read operation
- Write mistake prevention function
 - » Write prohibition at power on
 - » Write prohibition by command code
 - » Write mistake prevention function at low voltage
- Self-timed programming cycle
- Program condition display by READY / BUSY
- Compact package SOP8/SOP-J8/SSOP-B8/TSSOP-B8/MSOP8/ TSSOP-B8J/DIP-T8/VSON008X2030
- More than 40 years data retention
- More than 1 million write cycles
- Initial delivery state all addresses FFFFh



BR93G86-3B

Capacity	Bit Format	Туре	Power Source Voltage	Package
	16Kbit 1024×16	BR93G86-3B		DIP-T8
		BR93G86F-3B	1.7V to 5.5V	SOP8
		BR93G86FJ-3B		SOP-J8
16Kbit		BR93G86FV-3B		SSOP-B8
ΙΟΚΟΙΙ		BR93G86FVT-3B		TSSOP-B8
		BR93G86FVJ-3B		TSSOP-B8J
	BR93G86FVM-3B		MSOP8	
		BR93G86NUX-3B		VSON008X2030

*1 DIP-T8 is not halogen free package

OProduct structure : Silicon monolithic integrated circuit OThis product is not designed protection against radioactive rays

Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit	Remarks
Supply voltage	VCC	-0.3 to +6.5	V	
		0.80 (DIP-T8)		When using at Ta=25°C or higher 8.0mW to be reduced per 1°C.
		0.45 (SOP8)		When using at Ta=25°C or higher 4.5mW to be reduced per 1°C.
		0.45 (SOP-J8)		When using at Ta=25°C or higher 4.5mW to be reduced per 1°C.
Permissible	Pd	0.30 (SSOP-B8)	w	When using at Ta=25°C or higher 3.0mW to be reduced per 1°C.
dissipation	Pu	0.33 (TSSOP-B8)	vv	When using at Ta=25°C or higher 3.3mW to be reduced per 1°C.
		0.31 (TSSOP-B8J)		When using at Ta=25°C or higher 3.1mW to be reduced per 1°C.
		0.31 (MSOP8)		When using at Ta=25°C or higher 3.1mW to be reduced per 1°C.
		0.30 (VSON008X2030)		When using at Ta=25°C or higher 3.0mW to be reduced per 1°C.
Storage temperature	Tstg	-65 to +150	°C	
Operating temperature	Topr	-40 to +85	°C	
Input voltage/ Output voltage	-	-0.3 to Vcc+1.0	V	The Max value of Input voltage/Output voltage is not over 6.5V. When the pulse width is 50ns or less, the Min value of Input voltage/Output voltage is not under -0.8V.
Junction temperature	Tjmax	150	°C	Junction temperature at the storage condition

Memory cell characteristics (VCC=1.7~5.5V)

Decemeter		Limit	Unit	Condition	
Parameter	Min.	Тур.	Max.	Unit	Condition
Write cycles *1	1,000,000	-	-	Times	Ta=25°C
Data retention ^{*1}	40	-	-	Years	Ta=25°C

OShipment data all address FFFFh

*1 Not 100% TESTED

Recommended Operation Ratings

Parameter	Symbol	Limits	Unit
Supply voltage	VCC	1.7~5.5) (
Input voltage	VIN	0~VCC	V

●DC characteristics (Unless otherwise specified, VCC=1.7~5.5V, Ta=-40~+85°C)

		Limits					
Parameter	Symbol	Min.	Тур.	Max.	Unit	Condition	
Input low voltage	VIL	-0.3 ^{*1}	-	0.3VCC	V	1.7V≦VCC≦5.5V	
Input high voltage	Vін	0.7VCC	-	VCC+1.0	V	1.7V≦VCC≦5.5V	
Output low voltage 1	Vol1	0	-	0.4	V	IoL=2.1mA, 2.7V≦VCC≦5.5V	
Output low voltage 2	Vol2	0	-	0.2	V	Ιοι=100μΑ	
Output high voltage 1	VOH1	2.4	-	VCC	V	Іон=-0.4mA, 2.7V≦VCC≦5.5V	
Output high voltage 2	Voh2	VCC-0.2	-	VCC	V	Іон=-100µА	
Input leakage current1	ILI1	-1	-	+1	μA	VIN=0V~VCC(CS,SK,DI)	
Output leakage current	Ilo	-1	-	+1	μA	Vout=0V~VCC, CS=0V	
	loor	-	-	1.0	mA	VCC=1.7V, fsk=1MHz, te/w=5ms (WRITE)	
	ICC1	-	-	2.0	mA	VCC=5.5V ,f _{SK} =3MHz, t _{E/W} =5ms (WRITE)	
Supply surrent	loop	-	-	0.5	mA	fsĸ=1MHz (READ)	
Supply current	ICC2	-	-	1.0	mA	fsĸ=3MHz (READ)	
	loop	-	-	2.0	mA	VCC=2.5V, fsk=1MHz tew=5ms (WRAL, ERAL)	
	Іссз	-	-	3.0	mA	VCC=5.5V ,fsk=3MHz tew=5ms (WRAL, ERAL)	
Standby current	ISB1	-	-	2.0	μA	CS=0V	

*1 When the pulse width is 50ns or less, the Min value of V_{IL} is admissible to -0.8V.

●AC characteristics (Unless otherwise specified, VCC=1.7~2.5V, Ta=-40~+85°C)

Deremeter	Symbol		l locit		
Parameter		Min.	Тур.	Max.	Unit
SK frequency	f _{sк}	-	-	1	MHz
SK high time	tsкн	250	-	-	ns
SK low time	t _{SKL}	250	-	-	ns
CS low time	tcs	250	-	-	ns
CS setup time	t _{css}	200	-	-	ns
DI setup time	t _{DIS}	100	-	-	ns
CS hold time	tсsн	0	-	-	ns
DI hold time	t _{DIH}	100	-	-	ns
Data "1" output delay	tPD1	-	-	400	ns
Data "0" output delay	t _{PD0}	-	-	400	ns
Time from CS to output establishment	ts∨	-	-	400	ns
Time from CS to High-Z	t _{DF}	-	-	200	ns
Write cycle time	t _{E/W}	-	-	5	ms

(Unless otherwise specified, VCC=2.5~4.5V, Ta=-40~+85°C)

Deveryoter	Symbol		1.1		
Parameter		Min.	Тур.	Max.	Unit
SK frequency	fsк	-	-	2	MHz
SK high time	tsкн	230	-	-	ns
SK low time	tsĸ∟	200	-	-	ns
CS low time	tcs	200	-	-	ns
CS setup time	tcss	50	-	-	ns
DI setup time	t _{DIS}	100	-	-	ns
CS hold time	tсsн	0	-	-	ns
DI hold time	t _{DIH}	100	-	-	ns
Data "1" output delay	tPD1	-	-	200	ns
Data "0" output delay	t _{PD0}	-	-	200	ns
Time from CS to output establishment	tsv	-	-	150	ns
Time from CS to High-Z	t _{DF}	-	-	100	ns
Write cycle time	t _{E/W}	-	-	5	ms

(Unless otherwise specified, VCC=4.5~5.5V, Ta=-40~+85°C)

Deveryorten	Cumphel		1.1		
Parameter	Symbol	Min.	Тур.	Max.	Unit
SK frequency	fsк	-	-	3	MHz
SK high time	tsкн	100	-	-	ns
SK low time	tsĸ∟	100	-	-	ns
CS low time	tcs	200	-	-	ns
CS setup time	tcss	50	-	-	ns
DI setup time	t _{DIS}	50	-	-	ns
CS hold time	tсsн	0	-	-	ns
DI hold time	tын	50	-	-	ns
Data "1" output delay	t _{PD1}	-	-	200	ns
Data "0" output delay	t _{PD0}	-	-	200	ns
Time from CS to output establishment	tsv	-	-	150	ns
Time from CS to High-Z	t _{DF}	-	-	100	ns
Write cycle time	t _{E/W}	-	-	5	ms

Serial data input / output timing

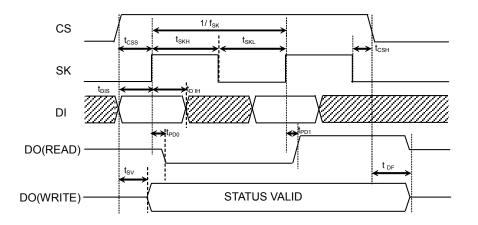


Figure 1. Sync data input / output timing

OData is taken by DI sync with the rise of SK.

OAt read operation, data is output from DO in sync with the rise of SK.

OThe STATUS signal at write (READY / $\overline{\text{BUSY}}$) is output after t_{CS} from the fall of CS after write command input, at the area DO where CS is high, and valid until the next command start bit is input. And, while CS is low, DO becomes High-Z.

OAfter completion of each mode execution, set CS low once for internal circuit reset, and execute the following operation mode.

O1/fsk is the SK clock cycle, even if fsk is maximum, the SK clock cycle can't be tskH(Min.)+tskL(Min.)

OFor "Write cycle time $t_{E/W}$ ", please see Figure 36,37,39,40.

OFor "CS low time t_{CS} ", please see Figure 36,37,39,40.

Block diagram

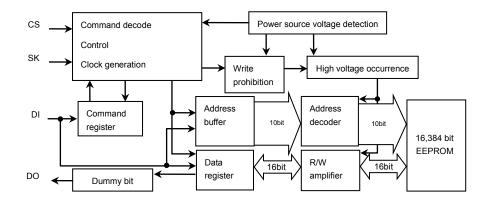


Figure 2. Block diagram

Pin Configuration

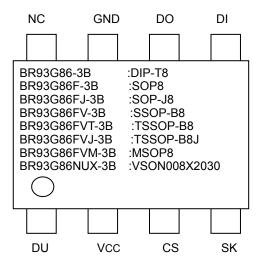


Figure 3. Pin Configuration

Pin Descriptions

Pin name	I/O	Function
DU	-	Don't use terminal ^{*1}
VCC	-	Supply voltage
CS	Input	Chip select input
SK	Input	Serial clock input
DI	Input	Start bit, ope code, address, and serial data input
DO	Output	Serial data output, READY / BUSY STATUS display output
GND	-	All input / output reference voltage, 0V
NC	-	Non connected terminal ^{*1}

*1 Terminals not used may be set to any of high, low, and OPEN

Typical Performance Curves

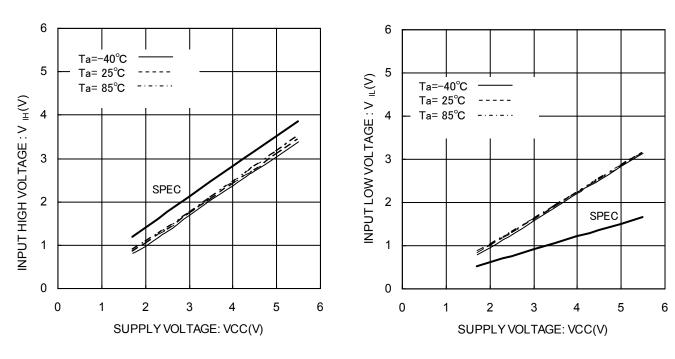


Figure 4. Input high voltage VIH(CS,SK,DI)

Figure 5. Input low voltage VIL(CS,SK,DI)

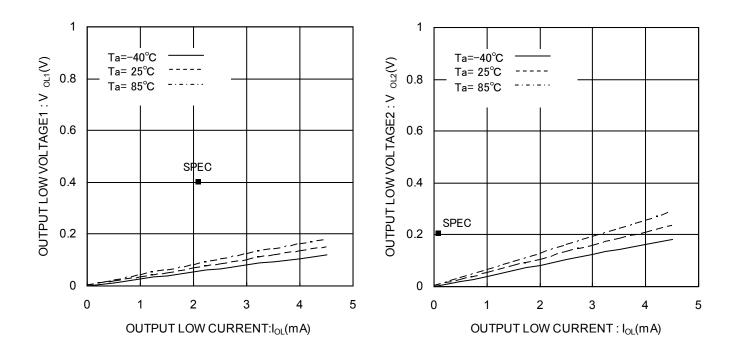
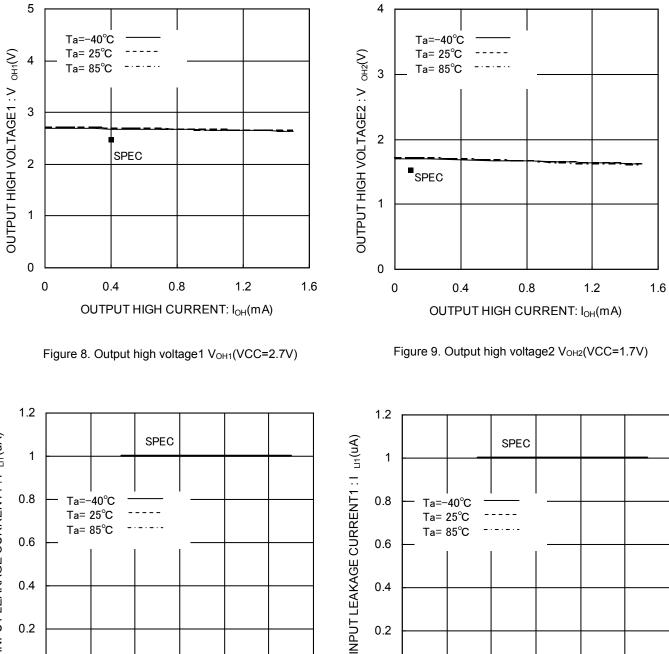


Figure 6. Output low voltage1 V_{OL1}(VCC=2.7V)

Figure 7. Output low voltage2 VoL2(VCC=1.7V)

Typical Performance Curves - Continued



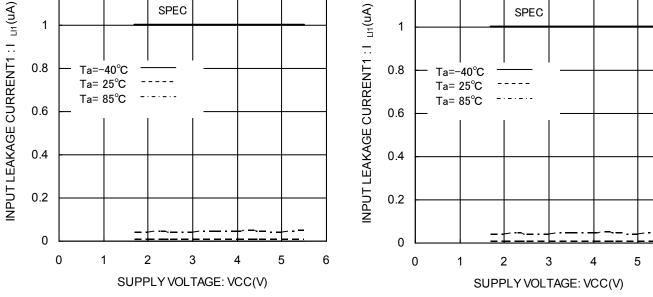
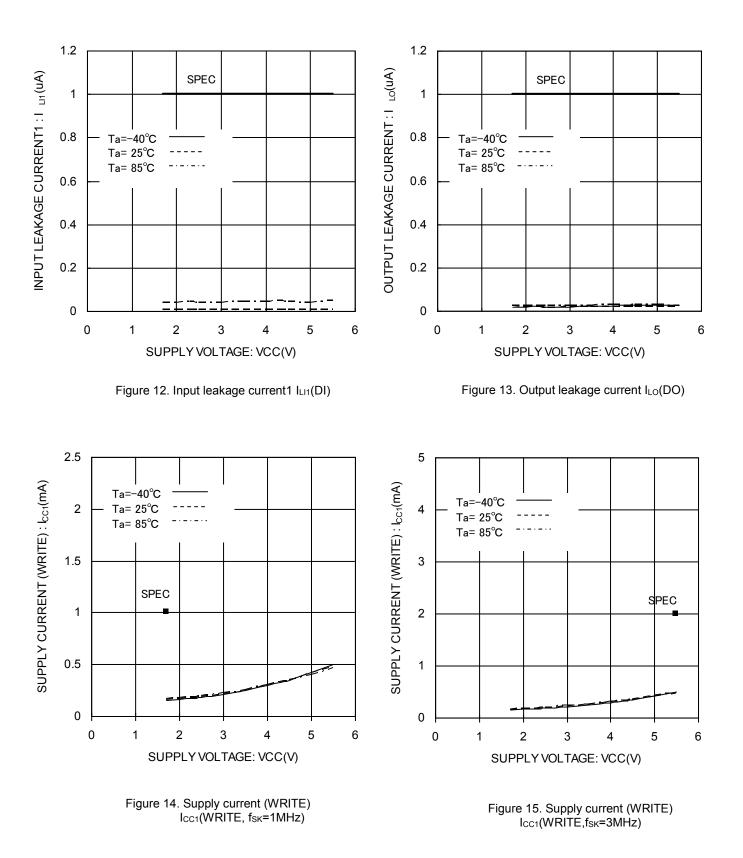


Figure 10. Input leakage current1 ILI1 (CS)

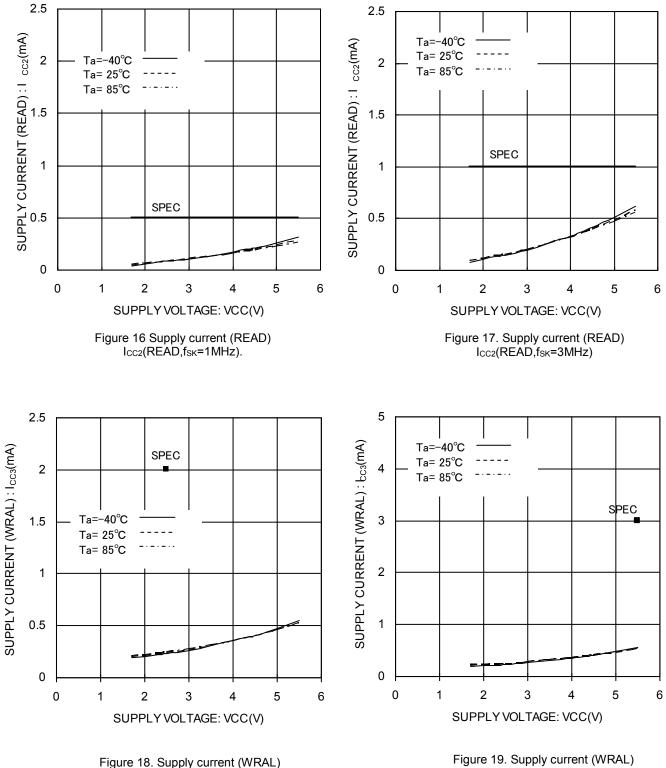
Figure 11. Input leakage current1 ILI1(SK)

6

Typical Performance Curves - Continued



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ICC3(WRAL, fsk=1MHz)

Icc3(WRAL, fsk=3MHz)

Typical Performance Curves - Continued

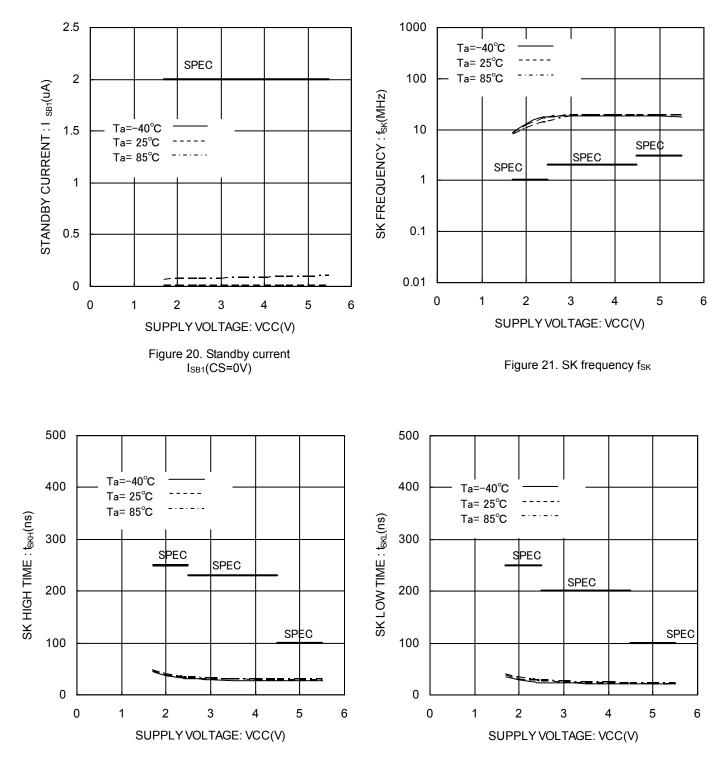
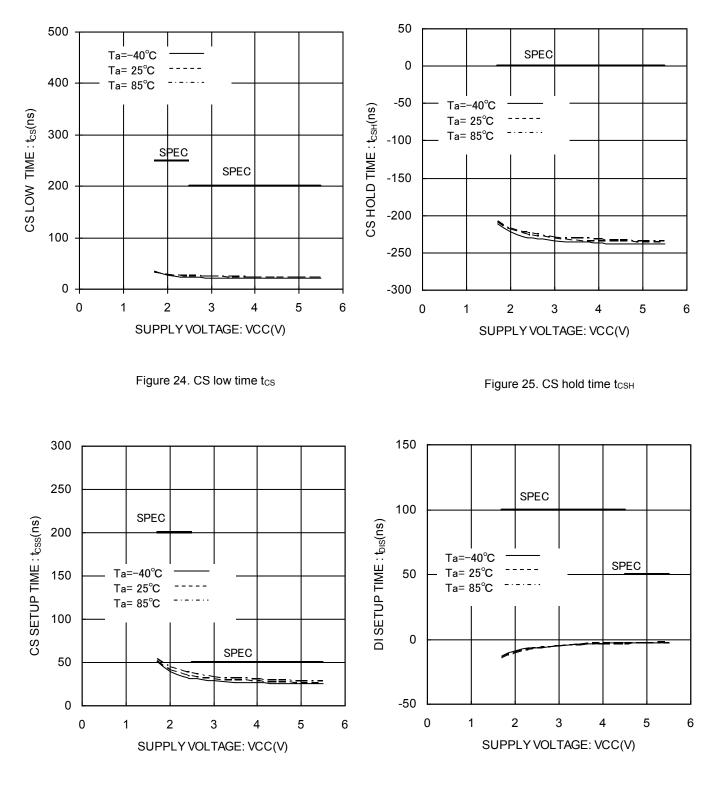
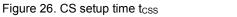


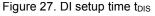


Figure 23. SK low time $t_{\mbox{\scriptsize SKL}}$

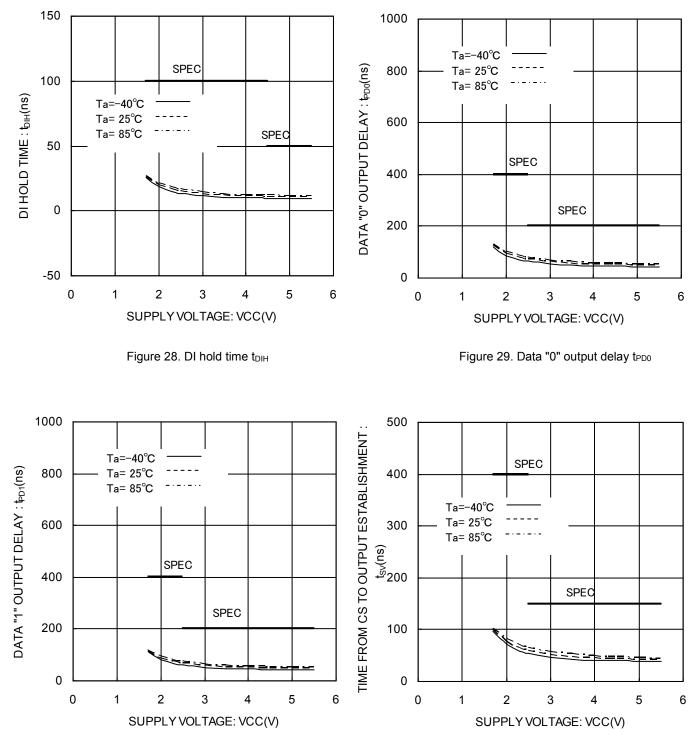
●Typical Performance Curves - Continued







Typical Performance Curves - Continued



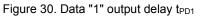


Figure 31. Time from CS to output establishment $t_{\mbox{\scriptsize SV}}$

●Typical Performance Curves - Continued

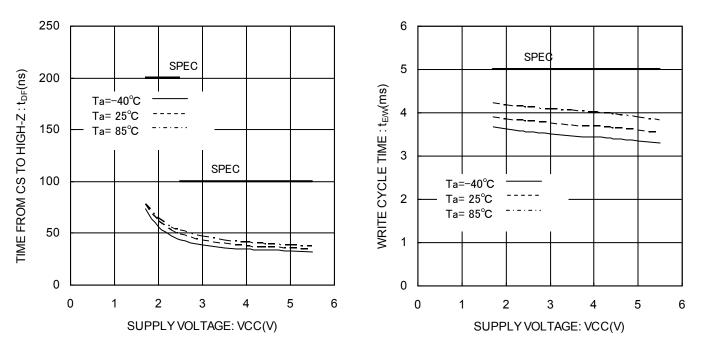


Figure 32. Time from CS to High-Z t_{DF}

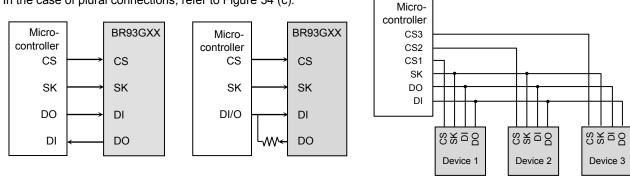
Figure 33. Write cycle time $t_{\text{E/W}}$

Description of operations

Communications of the MicroWire BUS are carried out by SK (serial clock), DI (serial data input), DO (serial data output), and CS (chip select) for device selection.

When to connect one EEPROM to a microcontroller, connect it as shown in Figure 34(a) or Figure 34(b). When to use the input and output common I/O port of the microcontroller, connect DI and DO via a resistor as shown in Figure 34(b) (Refer to pages 21, 22.), and connection by 3 lines is available.

In the case of plural connections, refer to Figure 34 (c).



(a). Connection by 4 lines

(b). Connection by 3 lines

(c). Connection example of plural devices

Figure 34. Connection method with microcontroller

Communications of the MicroWire BUS are started by the first "1" input after the rise of CS. This input is called a start bit. After input of the start bit, input ope code, address and data. Address and data are input all in MSB first manners. "0" input after the rise of CS to the start bit input is all ignored. Therefore, when there is limitation in the bit width of PIO of the microcontroller, input "0" before the start bit input, to control the bit width.

Command mode

Command	Start bit	Ope code	Address BR93G86-3 MSB of Address(Am) is A9	Data MSB of Data(Dx) is D15	Required clocks(n)
Read (READ) *1	1	10	A9,A8,A7,A6,A5,A4,A3,A2,A1,A0	D15~D0(READ DATA)	BR93G86-3:n=29
Write enable (WEN)	1	00	1 1 ******		
Write disable (WDS)	1	00	0 0 ******		BR93G86-3:n=13
Write (WRITE) *2	1	01	A9,A8,A7,A6,A5,A4,A3,A2,A1,A0	D15~D0(WRITE DATA)	BR93G86-3:n=29
Write all (WRAL) *2	1	00	0 1 ******	D15~D0(WRITE DATA)	BR93G00-3.11=29
Erase (ERASE)	1	11	A9,A8,A7,A6,A5,A4,A3,A2,A1,A0		BR93G86-3:n=13
Erase all (ERAL)	1	00	1 0 *******		DK93000-3.11=13

Input the address and the data in MSB first manners.

• As for *, input either "1" or "0".

*Start bit

Acceptance of all the commands of this IC starts at recognition of the start bit. The start bit means the first "1" input after the rise of CS.

*1 As for read, by continuous SK clock input after setting the read command, data output of the set address starts, and address data in significant order are sequentially output continuously. (Auto increment function)

*2 For write or write all commands, an internal erase or erase all is included and no separate erase or erase all is needed before write or write all command.

•Timing chart

1) Read cycle (READ)

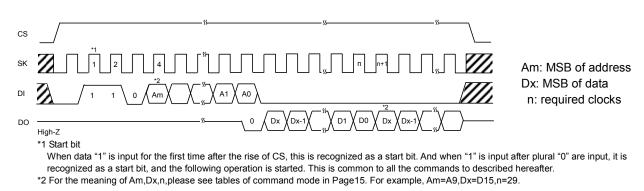


Figure 35. Read cycle

OWhen the read command is recognized, input address data (16bit) is output to serial. And at that moment, at taking A0, in sync with the rise of SK, "0" (dummy bit) is output. And, the following data is output in sync with the rise of SK.

This IC has an address auto increment function which is valid only at read command. This is the function where after the above read execution, by continuously inputting SK clock, the above address data is read sequentially. And, during the auto increment, keep CS at high.

2) Write cycle (WRITE)

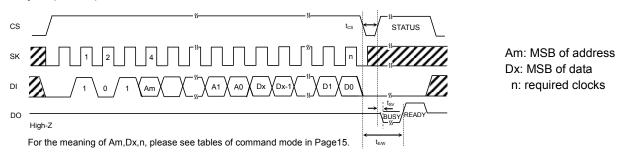
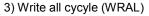


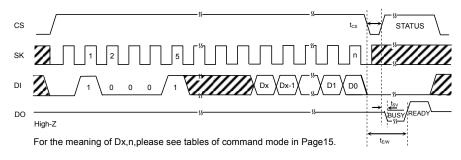
Figure 36. Write cycle

OIn this command, input 16bit data are written to designated addresses (Am~A0). The actual write starts by the fall of CS of D0 taken SK clock.

When STATUS is not detected (CS=low fixed),make sure Max 5ms time is in comforming with tew.

When STATUS is detected (CS=high), all commands are not accepted for areas where low (BUSY) is output from DO, therefore, do not input any command.





Dx: MSB of data n: required clocks

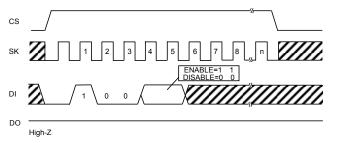
Figure 37. Write all cycle

OIn this command, input 16bit data is written simultaneously to all adresses. Data is not written continuously per one word but is written in bulk, the write time is only Max. 5ms in conformity with t_{EW}. In WRAL, STATUS can be detected in the same manner as in WRITE command.

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n: required clocks

4) Write enable (WEN) / disable (WDS) cycle

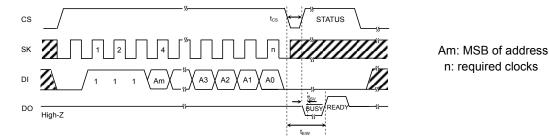


For the meaning of n,please see tables of command mode in Page15.

Figure 38. Write enable (WEN) / disable (WDS) cycle

- OAt power on, this IC is in write disable status by the internal RESET circuit. Before executing the write command, it is necessary to execute the write enable command. And, once this command is executed, it is valid unit the write disable command is executed or the power is turned off. However, the read command is valid irrespective of write enable / diable command. Input to SK after 6 clocks of this command is available by either "1" or "0", but be sure to input it.
- OWhen the write enable command is executed after power on, write enable status gets in. When the write disable command is executed then, the IC gets in write disable status as same as at power on, and then the write command is canceled thereafter in software manner. However, the read command is executable. In write enable status, even when the write command is input by mistake, write is started. To prevent such a mistake, it is recommended to execute the write disable command after completion of write.

5) Erase cycle (ERASE)



For the meaning of Am,n,please see tables of command mode in Page15.

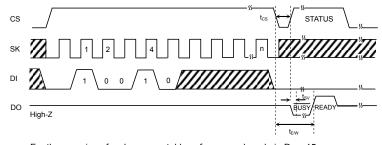
Figure 39. Erase cycle

OIn this command, data of the designated address is made into "1". The data of the designated address becomes "FFFFh".

Actual ERASE starts at the fall of CS after the fall of A0 taken SK clock.

In ERASE, STATUS can be detected in the same manner as in WRITE command.

⁶⁾ Erase all cycle (ERAL)



n: required clocks

For the meaning of n,please see tables of command mode in Page15.

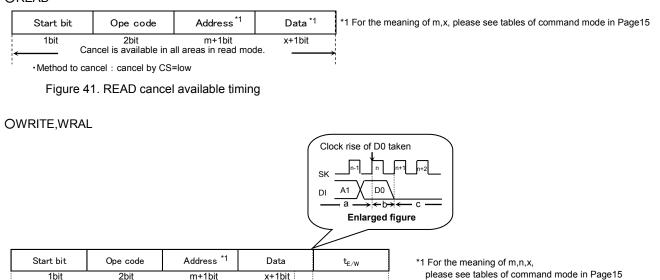


OIn this command, data of all addresses is made into "1". Data of all addresses becomes "FFFFh". Actual ERASE starts at the fall of CS after the fall of the n-th clock from the start bit input. In ERAL, STATUS can be detected in the same manner as in WRAL command.

Application

1)Method to cancel each command

OREAD



a : From start bit to the clock rise of D0 taken Cancel by CS=low

b : The clock rise of D0 taken and after Cancellation is not available by any means.

c : n+1 clock rise and after
Cancel by CS=low
However, when write is started in b area (CS is ended), cancellation is not available by any means.
And when SK clock is output continuously cancel function is not available.

Figure 42. WRITE, WRAL cancel available timing

- Note 1) If VCC is made OFF in this area, designated address data is not guaranteed, therefore write once again is suggested.
- Note 2) If CS is started at the same timing as that of the SK rise, write execution/cancel becomes unstable, therefore, it is recommended to fall in SK=low area. As for SK rise, recommend timing of t_{CSH} or higher.

OERASE, ERAL

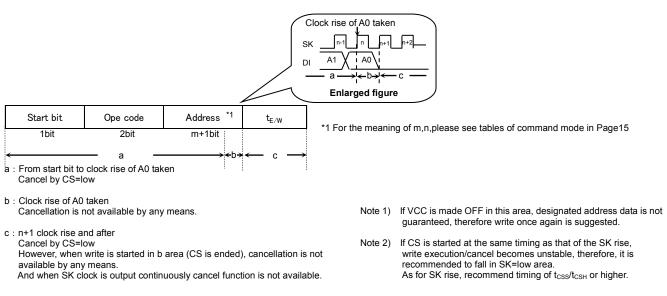


Figure 43. ERASE, ERAL cancel available timing

2) At standby

When CS is low, even if SK,DI,DO are low, high or with middle electric potential, current does not over I_{SB1} Max.

3) I/O peripheral circuit

3-1) Pull down CS.

By making CS=low at power ON/OFF, mistake in operation and mistake write are prevented.

OPull down resistance Rcs of CS pin

To prevent mistake in operation and mistake write at power ON/OFF, CS pull down resistance is necessary. Select an appropriate value to this resistance value from microcontroller V_{OH} , I_{OH} , and V_{IL} characteristics of this IC.

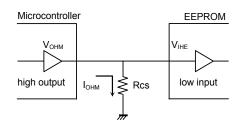


Figure 44. CS pull down resistance

Example) When VCC =5V, V_{IHE}=2V, V_{OHM}=2.4V, I_{OHM}=2mA, from the equation ①,

$$\operatorname{Rcs} \geq \frac{2.4}{2 \times 10^{-3}}$$

∴ Rcs ≧ 1.2 [kΩ]

With the value of Rpd to satisfy the above equation, V_{OHM} becomes 2.4V or higher, and V_{IHE} (=2.0V), the equation 2 is also satisfied.

• V_{IHE} : EEPROM VIH specifications

• V_{OHM} : Microcontroller V_{OH} specifications

• IOHM : Microcontroller IOH specifications

3-2) DO is available in both pull up and pull down.

Do output always is High-Z except in READY / BUSY STATUS and data output in read command. Malfunction may occur when High-Z is input to the microcontroller port connected to DO, it is necessary to pull down and pull up DO. When there is no influence upon the microcontroller operations, DO may be OPEN. If DO is OPEN, and at timing to output STATUS READY, at timing of CS=high, SK=high, DI=high, EEPROM recognizes this as a start bit, resets READY output, and DO=High-Z, therefore, READY signal cannot be detected. To avoid such output, pull up DO pin for improvement.

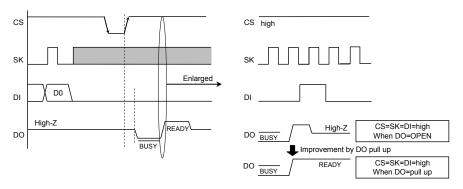


Figure 45. READY output timing at DO=OPEN

OPull up resistance Rpu and pull down resistance Rpd of DO pin

As for pull up and pull down resistance value, select an appropriate value to this resistance value from microcontroller V_{IH} , V_{IL} , and V_{OH} , I_{OH} , V_{OL} , I_{OL} characteristics of this IC.

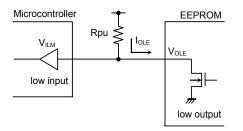


Figure 46. DO pull up resistance

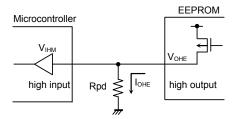


Figure 47. DO pull down resistance

$$Rpu \geq \frac{VCC - V_{OLE}}{I_{OLE}} \quad \cdots \quad (3)$$

$$ole \leq V_{ILM} \quad \cdots \quad (4)$$

Example) When VCC =5V, V_{OLE}=0.4V, I_{OLE}=2.1mA, V_{ILM}=0.8V, from the equation (3),

Rpu
$$\geq \frac{5-0.4}{2.1 \times 10^{-3}}$$

ν

With the value of Rpu to satisfy the above equation, V_{OLE} becomes 0.4V or below, and with V_{ILM} (=0.8V), the equation ④ is also satisfied.

- VOLE : EEPROM Vol specifications
- IOLE : EEPROM IOL specifications
- VILM : Microcontroller VIL specifications

$$Rpd \geq \frac{V_{OHE}}{I_{OHE}} \quad \cdots \quad (5)$$
$$V_{OHE} \geq V_{IHM} \quad \cdots \quad (6)$$

Example) When VCC =5V, V_{OHE} =VCC-0.2V, I_{OHE} =0.1mA, V_{IHM} =VCC \times 0.7V from the equation (5),

Rpd
$$\geq \frac{5-0.2}{0.1 \times 10^{-3}}$$

Rpd ≧ 48 [kΩ]

With the value of Rpd to satisfy the above equation, V_{OHE} becomes 2.4V or below, and with V_{IHM} (=3.5V), the equation 6 is also satisfied.

• V_{OHE} : EEPROM V_{OH} specifications

• I_{OHE} : EEPROM I_{OH} specifications

· VIHM : Microcontroller VIH specifications

OREADY / BUSY STATUS display (DO terminal)

This display outputs the internal STATUS signal. When CS is started after t_{CS} from CS fall after write command input, high or low is output.

 R/\overline{B} display=low (\overline{BUSY}) = write under execution

 $rac{DSTATUS}{DSTATUS}$ After the timer circuit in the IC works and creates the period of t_{EW}, this timer circuit completes automatically. And the memory cell is written in the period of t_{EW}, and during this period, other command is not accepted.

.....

 R/\overline{B} display = high (READY) = command wait STATUS

(DO STATUS) After t_{EW} (max.5ms) the following command is accepted.

Therefore, CS=high in the period of t_{EW} , and If signals are input in SK, DI, malfunction may occur, therefore, DI=low in the area

CS=high. (Especially, in the case of shared input port, attention is required.)

*Do not input any command while STATUS signal is output. Command input in BUSY area is cancelled, but command input in READY area is accepted. Therefore, STATUS READY output is cancelled, and malfunction and mistake write may occur.

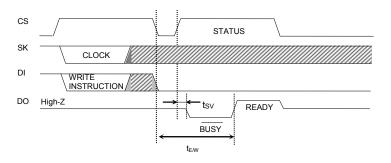


Figure 48. READY/BUSY STATUS output timing chart

4) When to directly connect DI and DO

This IC has independent input terminal DI and output terminal DO, and separate signals are handled on timing chart, meanwhile, by inserting a resistance R between these DI and DO terminals, it is possible to carry out control by 1 control line.

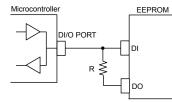
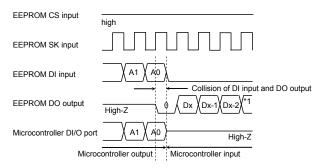


Figure 49. DI, DO control line common connection

OData collision of microcontroller DI/O output and DO output and feedback of DO output to DI input of EEPROM. Drive from the microcontroller DI/O output to DI input of EEPROM on I/O timing, and output signal from DO output of EEPROM occur at the same time in the following points.

4-1) 1 clock cycle to take in A0 address data at read command Dummy bit "0" is output to DO terminal.

 \rightarrow When address data A0 = "1" input, through current route occurs.



*1 X=15, for the meaning of x , please see tables of command mode in Page15.



4-2) Timing of CS = high after write command. DO terminal in READY / BUSY function output.

When the next start bit input is recognized, High-Z gets in.

→Especially, at command input after write, when CS input is started with microcontroller DI/O output low, READY output high is output from DO terminal, and through current route occurs.

Feedback input at timing of these (4-1) and (4-2) does not cause disorder in basic operations, if resistance R is inserted.

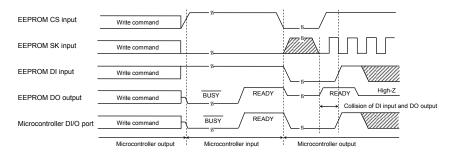
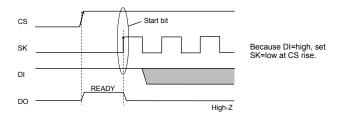


Figure 51. Collision timing at DI, DO direct connection

Note) As for the case (4-2), attention must be paid to the following.

When STATUS READY is output, DO and DI are shared, DI=high and the microcontroller DI/O=High-Z or the microcontroller DI/O=high, if SK clock is input, DO output is input to DI and is recognized as a start bit, and malfunction may occur. As a method to avoid malfunction, at STATUS READY output, set SK=low, or start CS within 4 clocks after high of READY signal is output.





OSelection of resistance value R

The resistance R becomes through current limit resistance at data collision. When through current flows, noises of power source line and instantaneous stop of power source may occur. When allowable through current is defined as I, the following relation should be satisfied. Determine allowable current amount in consideration of impedance and so forth of power source line in set. And insert resistance R, and set the value R to satisfy EEPROM input level V_{IH}/V_{IL} even under influence of voltage decline owing to leak current and so forth. Insertion of R will not cause any influence upon basic operations.

- 4-3) Address data A0 = "1" input, dummy bit "0" output timing
 - (When microcontroller DI/O output is high, EEPROM DO outputs low, and high is input to DI)
 - Make the through current to EEPROM 10mA or below.
 - See to it that the level V_{IH} of EEPROM should satisfy the following.

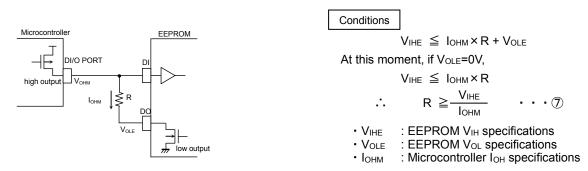
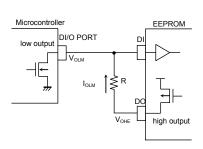


Figure 53. Circuit at DI, DO direct connection (Microcontroller DI/O high output, EEPROM low output)

4-4) DO STATUS READY output timing

- (When the microcontroller DI/O is low, EEPROM DO output high, and low is input to DI)
- Set the EEPROM input level VIL so as to satisfy the following.



Conditions
$$V_{ILE} \ge V_{OHE} - I_{OLM} \times R$$
As this moment, V_{OHE} =VCC $V_{ILE} \ge VCC - I_{OLM} \times R$ \therefore $R \ge \frac{VCC - V_{ILE}}{I_{OLM}}$ $\cdot V_{ILE}$: EEPROM V_{IL} specifications $\cdot V_{OHE}$: EEPROM V_{OH} specifications

· I_{OLM} : Microcontroller I_{OL} specifications

Example) When VCC=5V, VOHM=5V, IOHM=0.4mA, VOLM=5V, IOLM=0.4mA,

From the equation (\overline{O}) ,

From the equation[®],

R ≧ <u>Vihe</u> Iohm	$R \geq \frac{VCC - V_{ILE}}{I_{OLM}}$
$R \ge \frac{3.5}{0.4 \times 10^{-3}}$	$R \ge \frac{5-1.5}{2.1 \times 10^{-3}}$
R ≧ 8.75 [kΩ] ···9	$\therefore \qquad R \ge 1.67 [k\Omega] \qquad \cdots \qquad \textcircled{1}$

Therefore, from the equations (9) and (10),

 \therefore R \geq 8.75 [k Ω]

Figure 54. Circuit at DI, DO direct connection (Microcontroller DI/O low output, EEPROM high output)

....

5) I/O equivalence circuit

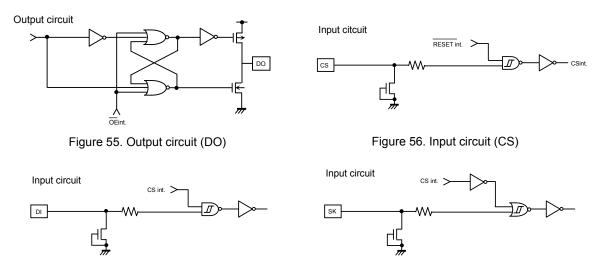


Figure 57. Input circuit (DI)

Figure 58. Input circuit (SK)

6) Power-Up/Down conditions

OAt power ON/OFF, set CS low.

When CS is high, this IC gets in input accept status (active). If power is turned on in this status, noises and the likes may cause malfunction, mistake write or so. To prevent these, at power ON, set CS low. (When CS is in low status all inputs are cancelled.) And at power decline, owing to power line capacity and so forth, low power status may continue long. At this case too, owing to the same reason, malfunction, mistake write may occur, therefore, at power OFF too, set CS low.

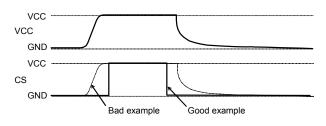


Figure 59. Timing at power ON/OFF

(Bad example) CS pin is pulled up to VCC

In this case, CS becomes high (active status), and EEPROM may have malfunction, mistake write owing to noise and the likes.

Even when CS input is High-Z, the status becomes like this case, which please note.

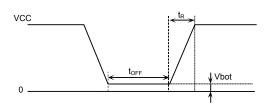
(Good example) It is low at power ON/OFF. Set 10ms or higher to recharge at power OFF. When power is turned on without observing this condition, IC internal circuit may not be reset, which please note.

OPOR citcuit

This IC has a POR (Power On Reset) circuit as a mistake write countermeasure. After POR operation, it gets in write disable status. The POR circuit is valid only when power is ON, and does not work when power is OFF. However, if CS is high at power ON/OFF, it may become write enable status owing to noises and the likes. For secure operations, observe the follwing conditions.

1. Set CS=low

2. Turn on power so as to satisfy the recommended conditions of t_R, t_{OFF}, Vbot for POR circuit operation.



Recommended conditions of tR, tOFF, Vbot

t _R	toff	Vbot	
10ms or below	10ms or higher	0.3V or below	
100ms or below	10ms or higher	0.2V or below	

Figure 60. Rise waveform diagram

OLVCC circuit

LVCC (VCC-Lockout) circuit prevents data rewrite operation at low power, and prevents wrong write. At LVCC voltage (Typ.=1.2V) or below, it prevent data rewrite

7)Noise countermeasures

OVCC noise (bypass capacitor)

When noise or surge gets in the power source line, malfunction may occur, therefore, for removing these, it is recommended to attach a by pass capacitor $(0.1\mu F)$ between IC VCC and GND, At that moment, attach it as close to IC as possible. And, it is also recommended to attach a bypass capacitor between board VCC and GND.

OSK noise

When the rise time of SK is long, and a certain degree or more of noise exists, malfunction may occur owing to clock bit displacement. To avoid this, a Schmitt trigger circuit is built in SK input. The hysteresis width of this circuit is set about 0.2V, if noises exist at SK input, set the noise amplitude 0.2Vp-p or below. And it is recommended to set the rise time of SK 100ns or below. In the case when the rise time is 100ns or higher, take sufficient noise countermeasures. Make the clock rise, fall time as small as possible.

Operational Notes

- (1) Described numeric values and data are design representative values, and the values are not guaranteed.
- (2) We believe that application circuit examples are recommendable, however, in actual use, confirm characteristics further sufficiently. In the case of use by changing the fixed number of external parts, make your decision with sufficient margin in consideration of static characteristics and transition characteristics and fluctuations of external parts and our LSI.
- (3) Absolute Maximum Ratings

If the absolute maximum ratings such as supply voltage and operating temperature range and so forth are exceeded, LSI may be destructed. Do not impress voltage and temperature exceeding the absolute maximum ratings. In the case of fear exceeding the absolute maximum ratings, take physical safety countermeasures such as fuses, and see to it that conditions exceeding the absolute maximum ratings should not be impressed to LSI.

(4) GND electric potential

Set the voltage of GND terminal lowest at any operating condition. Make sure that each terminal voltage is not lower than that of GND terminal in consideration of transition status.

(5) Heat design

In consideration of allowable loss in actual use condition, carry out heat design with sufficient margin.

(6) Terminal to terminal short circuit and wrong packaging

When to package LSI onto a board, pay sufficient attention to LSI direction and displacement. Wrong packaging may destruct LSI. And in the case of pin short between LSI terminals and terminals, terminals and power source, terminals and GND owing to unconnect use, LSI may be destructed.

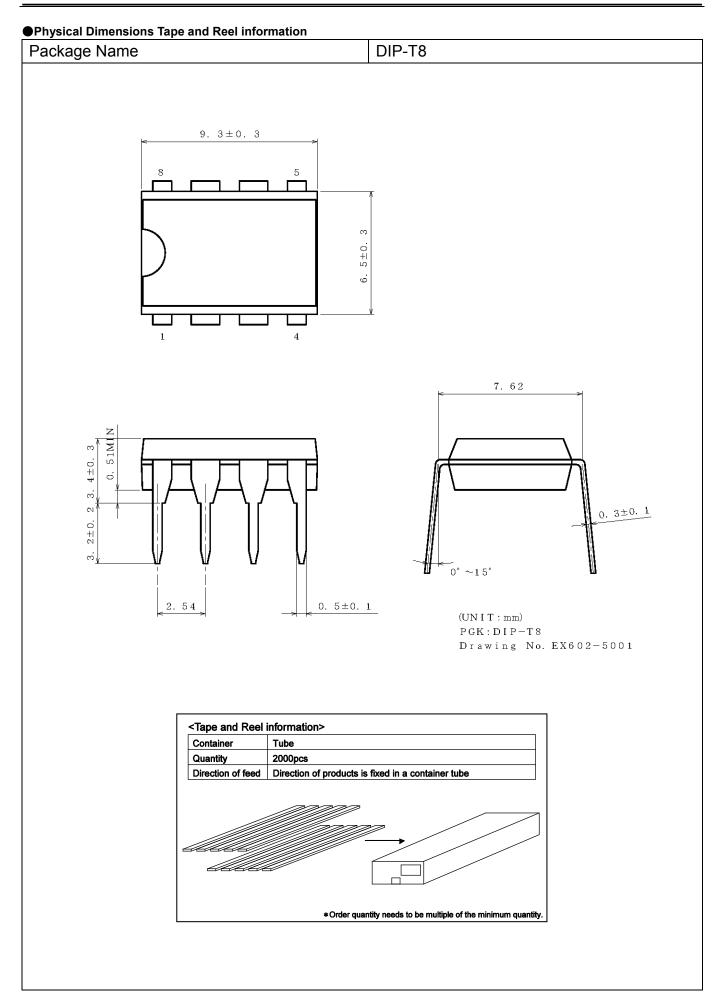
(7) Using this LSI in a strong electromagnetic field may cause malfunction, therefore, evaluate the design sufficiently.

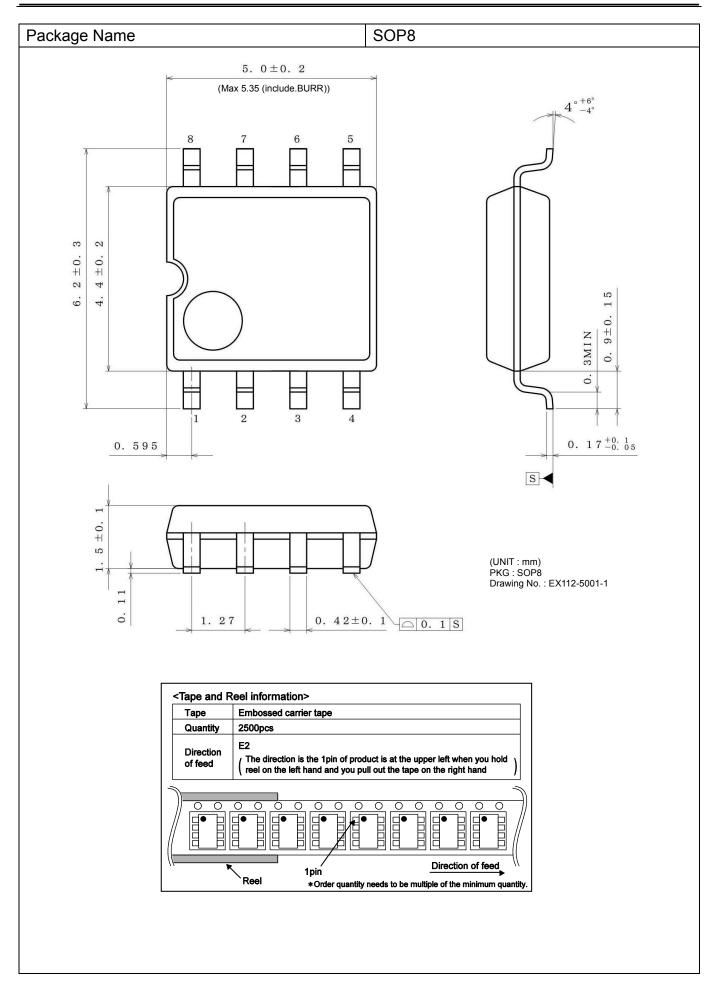
BF	र	9	3	G	8	6	x	x	x	—	3	x	x	X	x	X
				\top											\top	Τ
BUS ty 93 : M		Vire														
Operat Operat -40°C 1	ating	Volta	age													
Capac i 36=16k	ity	_				1										
Packag	ge															
Blank	:DI	P-T8														
F	:SC	P8														
FJ	:SC	P-J8														
=V	:SS	SOP-E	38													
FVT	:TS	SOP	-B8													
FVJ	:TS	SOP	-B8J													
FVM	:MS	SOP8														
NUX	:VS	SON0	08X20	30												
Proces	s co	de														
A :	Pin1 [,] Pin1	~8: C ~8: C	S, SK	DI, D0, D0, D0, D0, D0, D0, D0, D0, D0, D0), GNE), NC,	DU, V	CC res	spectiv	ely						
	Not excep	otion,	gen fr VSON	ree 1008X2 n free		lank"										
T : Blank:)% Sr 0% Si														

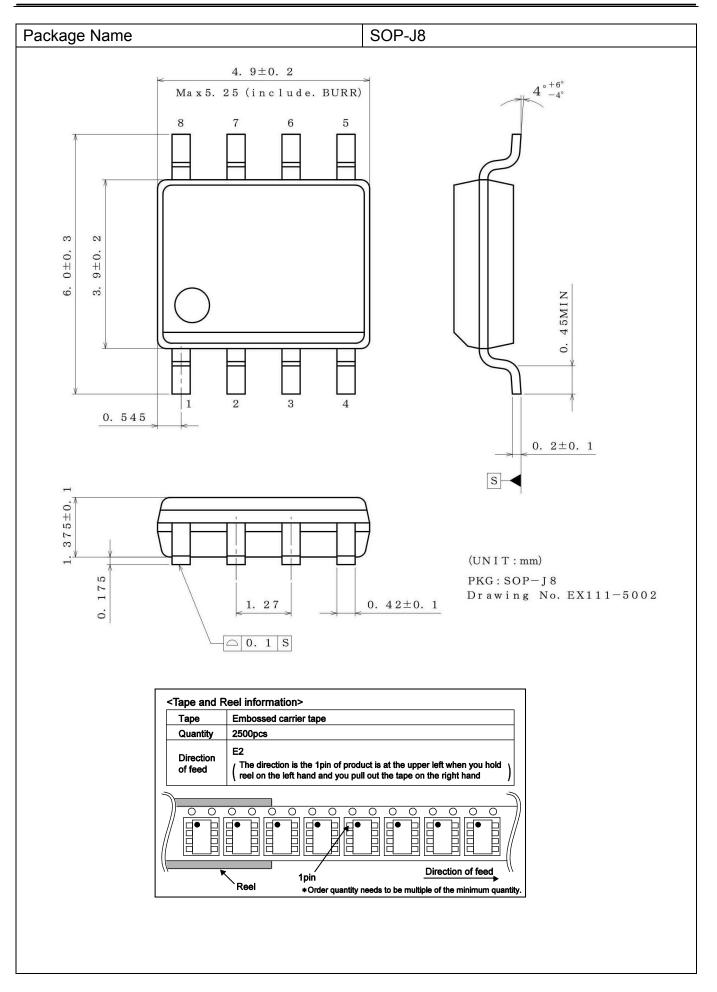
E2 : Embossed tape and reel (SOP8,SOP-J8, SSOP-B8,TSSOP-B8, TSSOP-B8J) TR : Embossed tape and reel (MSOP8, VSON008X2030) Blank : Tube

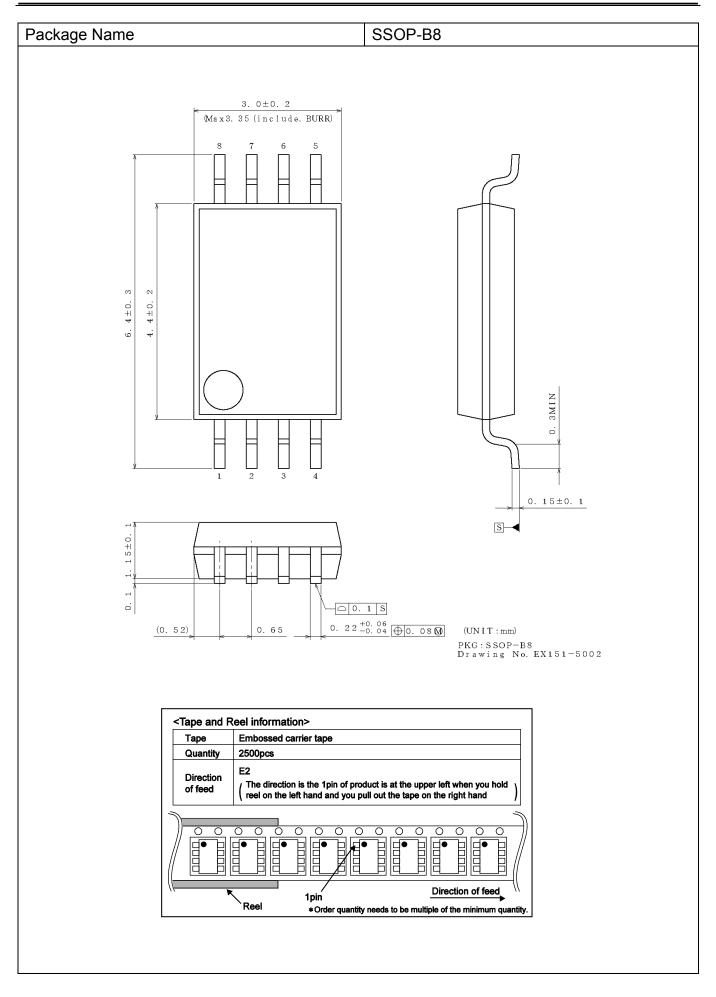
(DIP-T8)

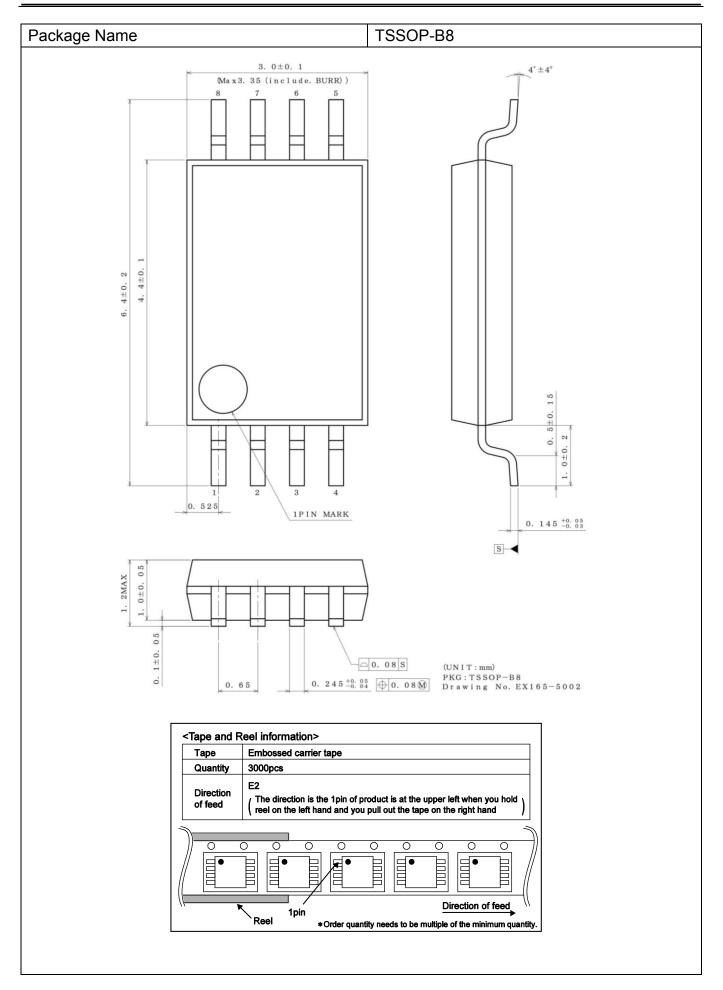
Orderable P	art Numbor	Pack	age	Remark		
Olderable P	art number	Туре	Quantity			
BR93G86	-3B	DIP-T8	Tube of 2000	Not Halogen free	100% Sn	
BR93G86F	-3BGTE2	SOP8	Reel of 2500	Halogen free	100% Sn	
BR93G86FJ	-3BGTE2	SOP-J8	Reel of 2500	Halogen free	100% Sn	
BR93G86FV	-3BGTE2	SSOP-B8	Reel of 2500	Halogen free	100% Sn	
BR93G86FVT	-3BGE2	TSSOP-B8	Reel of 3000	Halogen free	100% Sn	
BR93G86FVJ	-3BGTE2	TSSOP-B8J	Reel of 2500	Halogen free	100% Sn	
BR93G86FVM	-3BGTTR	MSOP8	Reel of 3000	Halogen free	100% Sn	
BR93G86NUX	-3BTTR	VSON008X2030	Reel of 4000	Halogen free	100% Sn	

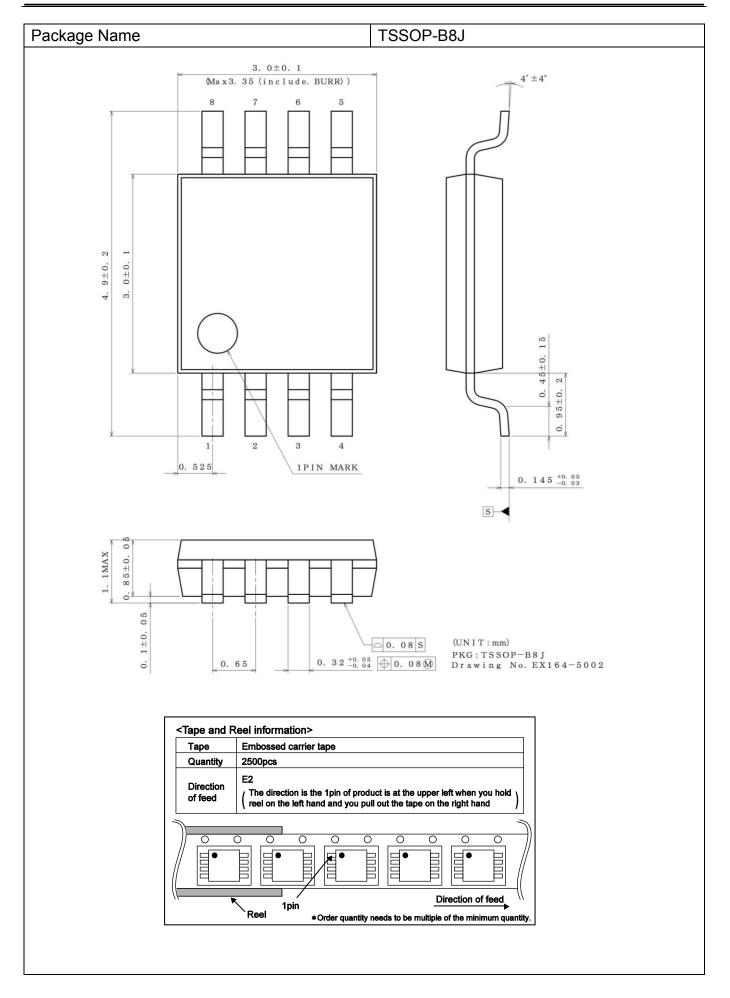


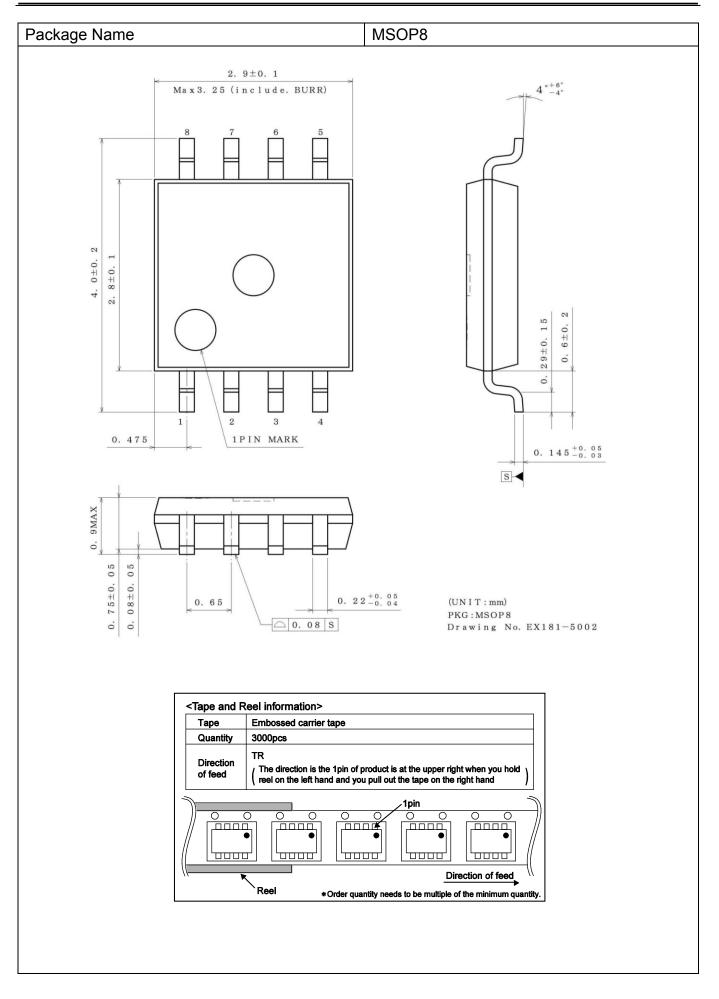


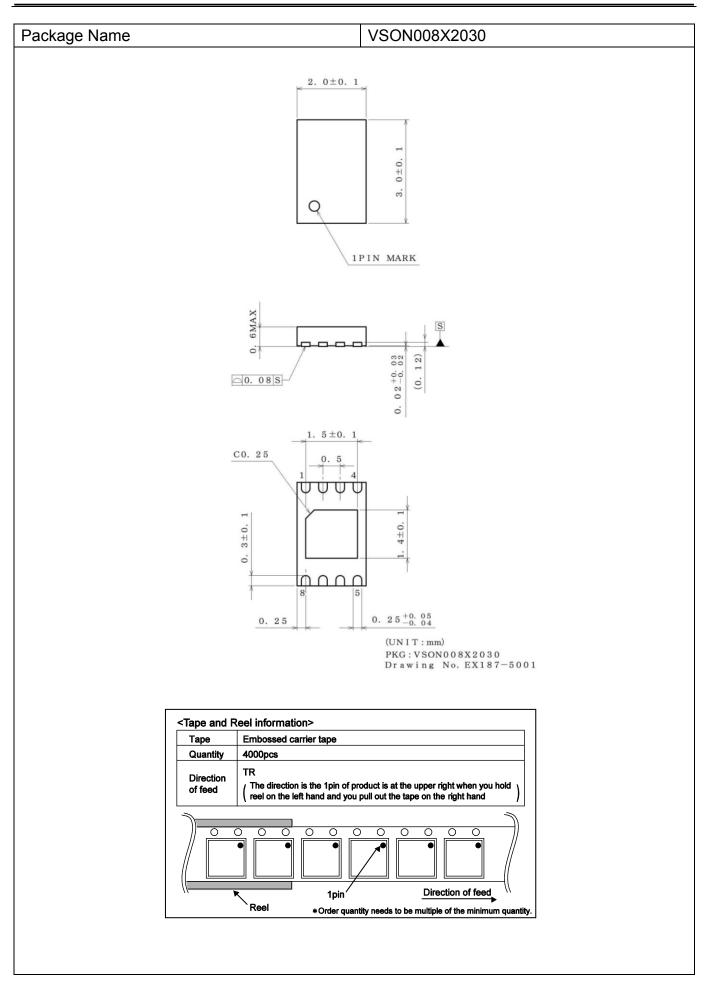




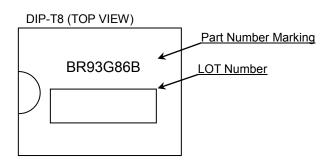


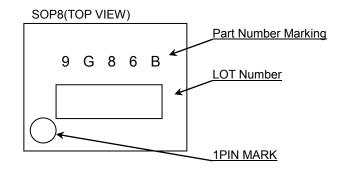


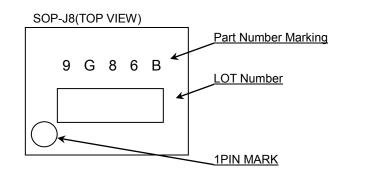


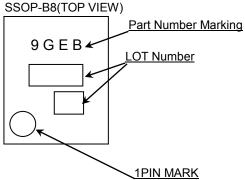


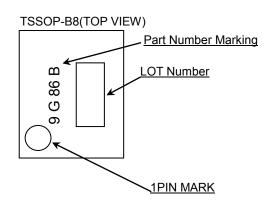
Marking Diagrams

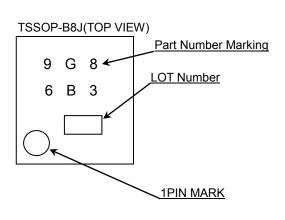


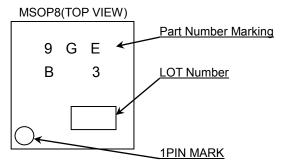


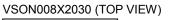


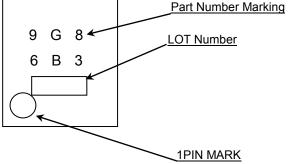












Revision History

Date Revision		Changes				
21.Jan.2013	001	New Release				
21.Dec.2015	002	 P.1 Change format of package line-up table. P.2 Change Remark of Power Dissipasion. P.26 Add the list of Part Numbering. P.27 Correct wrong size of Physical Dimensions. Wrong : The body thickness is 3.4±0.3 Correct : The leugth from high side of the body to the stopper of terminal is 3.4±0.3 P.28-34 Change the format of Physical Dimensions. 				

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JÁPAN	USA	EU	CHINA		
CLASSⅢ	CLASSⅢ	CLASS II b			
CLASSⅣ	CLASSIII	CLASSⅢ	CLASSⅢ		

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 - [d] Use of our Products in places where the Products are exposed to static electricity or electromagnetic waves
 - [e] Use of our Products in proximity to heat-producing components, plastic cords, or other flammable items
 - [f] Sealing or coating our Products with resin or other coating materials
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